## **Problem Statement**

PODEM (Path-Oriented Decision Making) is an Automatic Test Pattern Generation (ATPG) algorithm. The aim of this project is to implement the PODEM algorithm to generate test vectors for a given fault. Given a circuit and a fault location this algorithm will tell us whether the fault can be detected and a combination of input values which can detect the fault.

The output is a test if one exists, or the indication that the fault is untestable.

## **Assumptions**

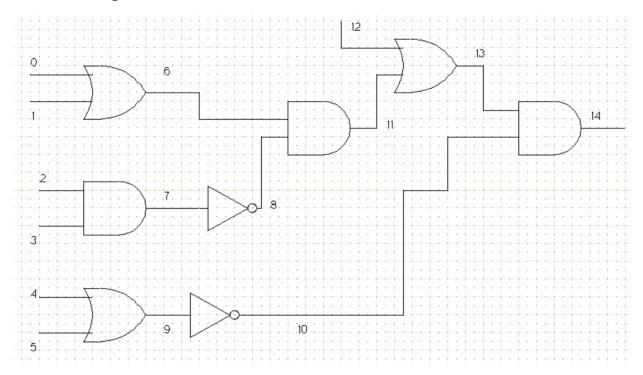
41 5x 12x

- Single stuck at fault
- Code written for 2 input type gates but can be easily extended to multiple input

## Input-Output Description

```
<out node> gate <in node1> <in node2>
Sentence printed on terminal
6 OR 0 1
7 AND 23
8 NOT 7
9 OR 4 5
9 NOT 10
13 OR 11 12
14 AND 10 13
-1 end
Enter observable node
14
Enter faulty node
10
Value of stuck at fault 0/1
1
Output obtained is
01
1 x
20
3 x
```

## Circuit Diagram



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